

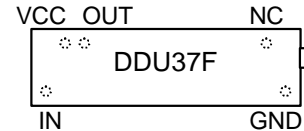
# MECHANICALLY VARIABLE TTL DELAY LINE (SERIES DDU37F)

data  
delay  
devices, inc. 

## FEATURES

- Ideal for "Set and Forget" applications
- Multi-turn adjustment screw (approx. 40 turns)
- Input & output fully TTL interfaced & buffered  
(10 T<sup>2</sup>L fan-out capability)
- **Resolution:** As low as 0.12ns
- **Minimum delay (T<sub>D0</sub>):** 6ns typical
- **Output rise time:** 2ns typical
- **Min. input pulse width:** 20% of maximum delay
- **Power dissipation:** 230mW maximum
- **Operating temperature:** 0° to 70°C (Commercial)  
-55° to 125°C (Military)
- **Temperature coefficient:** 100 PPM/°C

## PACKAGES



DDU37F-xx (Commercial)  
DDU37F-xxM (Military)  
xx = Dash number

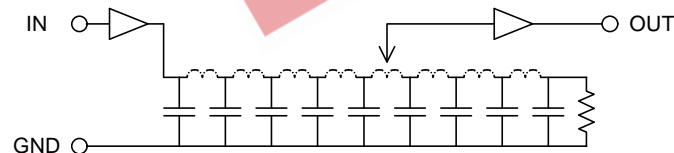
## FUNCTIONAL DESCRIPTION

The DDU37F-series device is a mechanically variable, FAST-TTL interfaced delay line. The signal input (IN) is reproduced at the tap output (OUT), shifted by an amount which can be adjusted between T<sub>D0</sub> and T<sub>D0</sub> + T<sub>DVAR</sub>, where T<sub>DVAR</sub> is given by the device dash number (See Table). The device operates from a single 5V supply and is TTL interfaced, capable of driving up to 10 TTL loads.

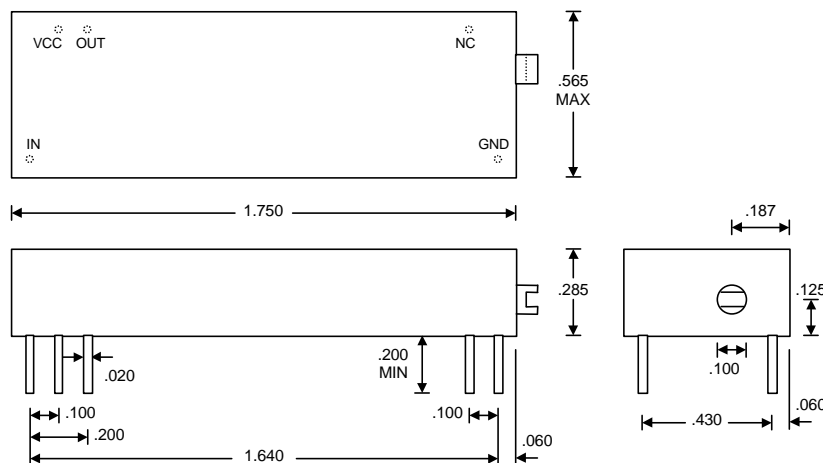
## PIN DESCRIPTIONS

IN Signal Input  
OUT Fixed Output  
VCC +5V  
GND Ground  
NC No connection

## SERIES SPECIFICATIONS



Functional Diagram



Package Dimensions

## DASH NUMBER SPECIFICATIONS

Part Number	T <sub>DVAR</sub> (ns)
DDU37F-25	15
DDU37F-30	20
DDU37F-40	30
DDU37F-50	40
DDU37F-60	50
DDU37F-70	60
DDU37F-80	70
DDU37F-100	90
DDU37F-120	100
DDU37F-150	130
DDU37F-200	180

Note: Other delay times available on request

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## APPLICATION NOTES

### HIGH FREQUENCY RESPONSE

The DDU37F tolerances are guaranteed for input pulse widths and periods greater than those specified in the test conditions. Although the device will function properly for pulse widths as small as 20% of the total delay and periods as small as 40% of the total delay (for a symmetric input), the delays may deviate from their values at low frequency. However, for a given input condition, the deviation will be repeatable from pulse to pulse. Contact technical support at Data

Delay Devices if your application requires device testing at a specific input condition.

### POWER SUPPLY BYPASSING

The DDU37F relies on a stable power supply to produce repeatable delays within the stated tolerances. A 0.1uf capacitor from VCC to GND, located as close as possible to the VCC pin, is recommended. A wide VCC trace and a clean ground plane should be used.

## DEVICE SPECIFICATIONS

TABLE 1: ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
DC Supply Voltage	V <sub>CC</sub>	-0.3	7.0	V	
Input Pin Voltage	V <sub>IN</sub>	-0.3	V <sub>DD</sub> +0.3	V	
Storage Temperature	T <sub>STRG</sub>	-55	150	C	
Lead Temperature	T <sub>LEAD</sub>		300	C	10 sec

TABLE 2: DC ELECTRICAL CHARACTERISTICS

(0C to 70C, 4.75V to 5.25V)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
High Level Output Voltage	V <sub>OH</sub>	2.5	3.4		V	V <sub>CC</sub> = MIN, I <sub>OH</sub> = MAX V <sub>IH</sub> = MIN, V <sub>IL</sub> = MAX
Low Level Output Voltage	V <sub>OL</sub>		0.35	0.5	V	V <sub>CC</sub> = MIN, I <sub>OL</sub> = MAX V <sub>IH</sub> = MIN, V <sub>IL</sub> = MAX
High Level Output Current	I <sub>OH</sub>			-1.0	mA	
Low Level Output Current	I <sub>OL</sub>			20.0	mA	
High Level Input Voltage	V <sub>IH</sub>	2.0			V	
Low Level Input Voltage	V <sub>IL</sub>			0.8	V	
Input Clamp Voltage	V <sub>IK</sub>			-1.2	V	V <sub>CC</sub> = MIN, I <sub>I</sub> = I <sub>IK</sub>
Input Current at Maximum Input Voltage	I <sub>IHH</sub>			0.1	mA	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7.0V
High Level Input Current	I <sub>IH</sub>			20	μA	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V
Low Level Input Current	I <sub>IL</sub>			-0.6	mA	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5V
Short-circuit Output Current	I <sub>OS</sub>	-60		-150	mA	V <sub>CC</sub> = MAX
Output High Fan-out				25	Unit	
Output Low Fan-out				12.5	Load	

## DELAY LINE AUTOMATED TESTING

### TEST CONDITIONS

#### INPUT:

**Ambient Temperature:**  $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$

**Supply Voltage (Vcc):**  $5.0\text{V} \pm 0.1\text{V}$

**Input Pulse:** High =  $3.0\text{V} \pm 0.1\text{V}$   
Low =  $0.0\text{V} \pm 0.1\text{V}$

**Source Impedance:**  $50\Omega$  Max.

**Rise/Fall Time:**  $3.0$  ns Max. (measured between  $0.6\text{V}$  and  $2.4\text{V}$ )

**Pulse Width:**  $PW_{\text{IN}} = 1.5 \times \text{Total Delay}$

**Period:**  $PER_{\text{IN}} = 10 \times \text{Total Delay}$

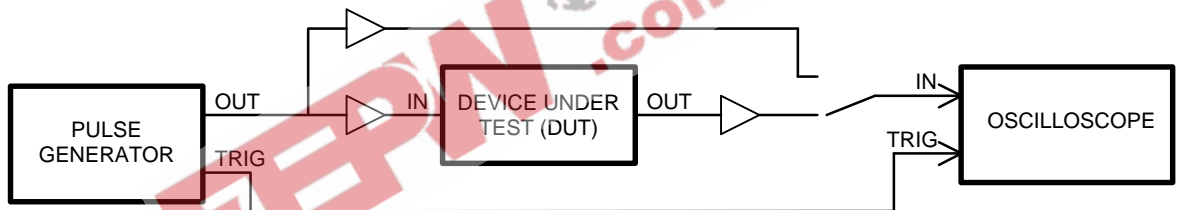
#### OUTPUT:

**Load:** 1 FAST-TTL Gate

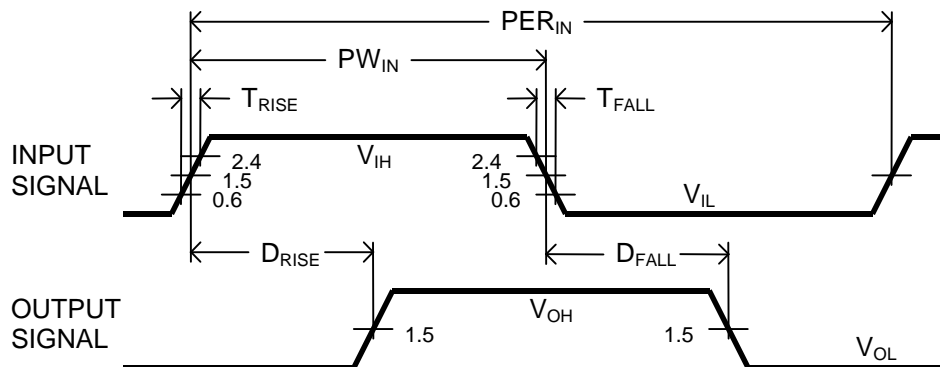
**C<sub>load</sub>:**  $5\text{pf} \pm 10\%$

**Threshold:**  $1.5\text{V}$  (Rising & Falling)

**NOTE:** The above conditions are for test only and do not in any way restrict the operation of the device.



Test Setup



Timing Diagram For Testing